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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/728,324	12/04/2003	Debendra Mallik	P16831	7342
28062 7590 08/01/2007 BUCKLEY, MASCHOFF & TALWALKAR LLC 50 LOCUST AVENUE NEW CANAAN, CT 06840			EXAMINER ANDUJAR, LEONARDO	
			ART UNIT	PAPER NUMBER
			2826	
			MAIL DATE	DELIVERY MODE
			08/01/2007	PAPER

**Please find below and/or attached an Office communication concerning this application or proceeding.**

The time period for reply, if any, is set in the attached communication.

<b>Office Action Summary</b>	Application No. 10/728,324	Applicant(s) MALLIK ET AL.	
	Examiner Leonardo Andújar	Art Unit 2826	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

#### Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

#### Status

- 1) ☒ Responsive to communication(s) filed on 5/03/2007.
- 2a) ☐ This action is **FINAL**. 2b) ☒ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

#### Disposition of Claims

- 4) ☒ Claim(s) 1,2,4-10,15 and 17-19 is/are pending in the application.
- 4a) Of the above claim(s) \_\_\_\_\_ is/are withdrawn from consideration.
- 5) ☐ Claim(s) \_\_\_\_\_ is/are allowed.
- 6) ☒ Claim(s) 1,2,4-10,15 and 17-19 is/are rejected.
- 7) ☐ Claim(s) \_\_\_\_\_ is/are objected to.
- 8) ☐ Claim(s) \_\_\_\_\_ are subject to restriction and/or election requirement.

#### Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☐ The drawing(s) filed on \_\_\_\_\_ is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.  
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).  
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

#### Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some \* c) ☐ None of:
1. ☐ Certified copies of the priority documents have been received.
  2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
  3. ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

\* See the attached detailed Office action for a list of the certified copies not received.

#### Attachment(s)

- |  |   |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892)  | 4) <input type="checkbox"/> Interview Summary (PTO-413)<br>Paper No(s)/Mail Date. _____ |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948)                                   | 5) <input type="checkbox"/> Notice of Informal Patent Application (PTO-152)             |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)<br>Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____  |

## DETAILED ACTION

### ***Continued Examination Under 37 CFR 1.114***

1. A request for continued examination under 37 CFR 1.114, including the fee set forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this application is eligible for continued examination under 37 CFR 1.114, and the fee set forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 3/27/2007 has been entered.

### ***Claim Rejections - 35 USC § 103***

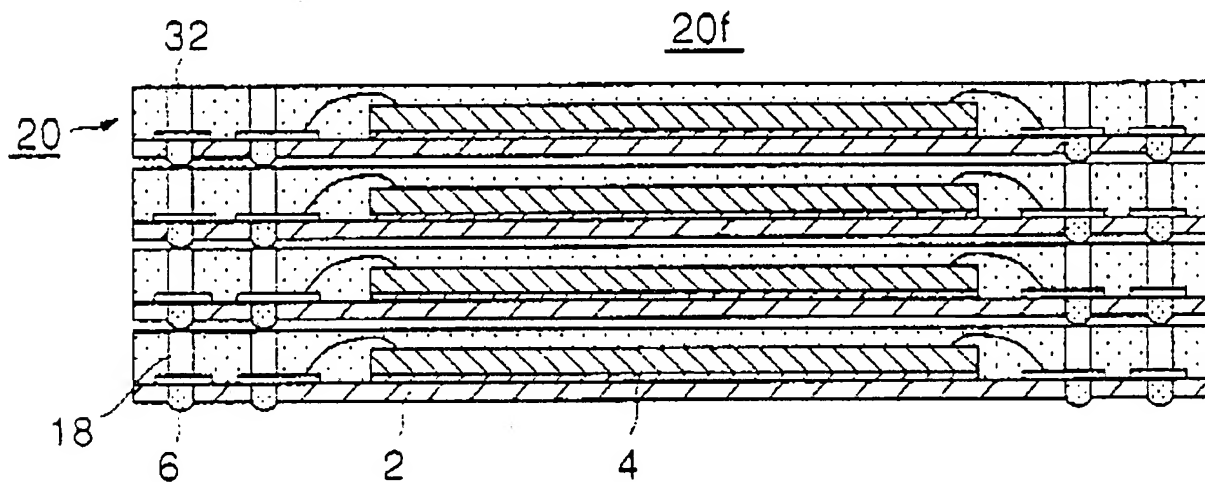
2. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

3. Claims 1, 2, 4-9 as being unpatentable over Taniguchi et al. (US 6,489,676 previously cited) in view of Lee (US 7,145,225) in further view of Somaki (US 5,641,113).

4. Regarding claim 1, Taniguchi (e.g. figs. 9 and 12) shows an apparatus comprising: a first integrated circuit die 4; a first integrated circuit package 2 connected to the first integrated circuit die; mold compound 8 in contact with the first integrated circuit die and the first integrated circuit package; a first interconnect 18 in contact with the first integrated circuit package; a second integrated circuit package 2; a second

interconnect or solder ball 6 in contact to the second integrated circuit package, wherein a first portion 18 of the first interconnect is in contact with the mold compound, wherein a second portion of the first interconnect (top side) is not in contact with the mold compound, wherein the mold defines an opening, and wherein a third portion (bottom portion) of the first interconnect is in contact with the first integrated circuit package, and the second interconnect or solder ball 6 is in contact with the first interconnect.



Taniguchi does not show that the second interconnect is in contact with the first interconnect within the opening also that the first interconnect is a solder ball. However, Lee (e.g. fig. 3) shows an interconnect having a first interconnect 15/16 and a second interconnect 34 wherein the second interconnect is in contact with the first interconnect within the opening whereas Somaki (e.g. fig. 6) teaches a first and a second interconnect (13 a, b) wherein the first and second interconnects are solder balls. According to Somaki this embodiment allows higher shear strain tolerances, greater reliability and higher conductivity (col. 3/lls. 30-40).



6. Regarding claim 4, Taniguchi shows a the second integrated circuit package is coupled to the mold compound (thermally).

7. Regarding claim 5, Taniguchi in view of Lee further in view of Somaki shows a second integrated circuit die 4 in contact with the second integrated circuit package 2; second mold compound 8 in contact with the second integrated circuit die and the second integrated circuit package; and a third interconnect/solder ball 18 connected with the second integrated circuit package, wherein a first portion (side surface) of the third interconnect is in contact with the second mold compound, and wherein a second portion (top surface) of the third interconnect is not in contact with the second mold compound, wherein the second mold compound defines a second opening, wherein the second portion of the third interconnection is recessed beneath the second opening, and wherein a third portion (bottom surface) of the third interconnect is in contact with the second integrated circuit package.

8. Regarding claim 6, Taniguchi in view of Lee further in view of Somaki shows a third integrated circuit package 2 (third package in upward direction); a fourth interconnect/solder ball 18b coupled to the third integrated circuit package, wherein the fourth interconnect is coupled to the third interconnect/solder ball (electrically).

9. Regarding claim 7, Taniguchi in view of Lee further in view of Somaki (e.g. fig. 18) shows a second integrated circuit 4a coupled to the integrated circuit die, in contact with the mold compound, and electrically coupled to the integrated circuit package.

10. Regarding claim 8, Taniguchi (e.g. figs. 9 and 12) shows an apparatus comprising: a first integrated circuit package substrate 2; a plurality of integrated circuit dies (4/4a) coupled to the first integrated circuit package substrate (e.g. thermally, electrically); a mold compound 8 in contact with the integrated circuit die and the first

integrated circuit package; a first interconnect 18 in contact with the first integrated circuit package substrate and electrically connected to one of the plurality of integrated circuits dies, a second integrated circuit package substrate 2; a second interconnect/solder ball 6 in contact to the second integrated circuit package substrate, wherein a first portion 18 (side surfaces) of the first interconnect is in contact with the mold compound, wherein a second portion (top portion) of the first interconnect is not in contact with the mold compound, the mold compound defining an opening, and wherein a third portion (bottom portion) of the first interconnect is in contact with the first integrated circuit package and the second interconnect is in contact with the first interconnect. Taniguchi does not show that the second portion of the first interconnect is recessed beneath the opening and wherein the first and second interconnect are connected within the opening and that the first interconnection is a solder ball. However, Lee (e.g. fig. 3) shows an interconnect having a first interconnect 15/16 and a second interconnect 34 wherein the second portion 16 of the first interconnect is recessed beneath the opening whereas Somaki (e.g. fig. 6) teaches a first and a second interconnect (13 a, b) wherein the first and second interconnects are solder balls. According to Somaki this embodiment allows higher shear strain tolerances, greater reliability and higher conductivity (col. 3/lis. 30-40). It would have been obvious to one of ordinary skill in the art at the time the invention was made to make the second portion of the first interconnect disclosed by Taniguchi recessed beneath the opening and to connect the first and second interconnects within the opening to make a package having a reduced thickness as taught by Lee (see col. 3/lis. 17-40) and to use solder

balls as first and second interconnects as suggested by Somaki to allow for higher shear strain tolerances, greater reliability and higher conductivity.

11. Regarding claim 9, Taniguchi shows a die attach material disposed between the first faces of each of the plurality of circuit package substrate (col. 1/ll. 43).

12. Claim 10 is rejected under 35 U.S.C. 103(a) as being unpatentable over Taniguchi et al. (US 6,489,676 previously cited) in view of Lee (US 7,145,225) further in view of Somaki (US 5,641,113) further in view of Takiar (US 5,422,435).

13. Regarding claim 10, Taniguchi in view of Lee further in view of Somaki shows most aspects of the instant invention except for a second integrated circuit in contact to the first integrated circuit die 4, in contact with the mold compound, and electrically couple the integrated circuit package. Takiar (e.g. fig. 8) shows a package comprising a stacked arrangement of semiconductor dies that provide a single circuit assembly. As shown in figure 5, a second integrated circuit die 174 is coupled to a first integrated circuit die 172 is in contact with the mold compound 25 (e.g. fig. 1), and is electrically couple the integrated circuit package 182. According to Takiar, this type of arrangement is used to decrease the size and weight of the device, as well as to improve its performance (col. 2/lls. 3-9). It would have been obvious to one of ordinary skill in the art at the time the invention was made to make the device disclosed by Taniguchi in view of Lee further in view of Somaki having two or more semiconductor dies wherein the second integrated circuit die is coupled to the first integrated circuit die, in contact with the mold compound, and electrically couple the integrated circuit



package in order to provide a single circuit assembly having a decreased size and weight as suggested by Takiar.

14. Claims 15 and 17-19 are rejected under 35 U.S.C. 103(a) as being unpatentable over Taniguchi et al. (US 6,489,676 previously cited) in view of Lee (US 7,145,225) further in view of Chang (US 20020196650) further in view of Somaki (US 5,641,113).

15. Regarding claim 15, Taniguchi (e.g. figs. 9 and 12) shows a system comprising: a first integrated circuit die 4; a first integrated circuit package 2 in contact with the first integrated circuit die; a mold compound 8 in contact with the first integrated circuit die and the first integrated circuit package; a first interconnect 18 in contact with the first integrated circuit package; a second integrated circuit die 4; second integrated circuit package 2 (e.g. fig. 12); a second interconnect/solder ball 6 in contact to the second integrated circuit package, wherein a first portion 18 of the first interconnect is in contact with the mold compound (i.e. side surface), wherein a second portion (i.e. top portion) of the first interconnect is not in contact with the mold compound, wherein the mold compound defines an opening and wherein a third portion (i.e. bottom surface) of the first interconnect is in contact with the first integrated circuit package. Taniguchi does not show that the system includes a double data rate memory and that the second portion of the first interconnect is recessed beneath the opening and wherein the first and second interconnect are connected within the opening and that the first interconnect is a solder ball. However, Chang teaches (e.g. fig. 2) a computer system including a double data rate memory (204-207) electrically coupled to an integrated circuit die 202. Chang teaches that under the mode of double data rate, the memory

can perform data access control during both the raising edge and falling edge of the system clock signal. Thus, the operation speed of the memory is fastened (pps. 005, 006 & 0028). Furthermore, Lee (e.g. fig. 3) shows an interconnect having a first interconnect 15/16 and a second interconnect 34 wherein the second portion 16 of the first interconnect is recessed beneath the opening. Also, shows that the first and second interconnect are in contact within the opening. Lee's embodiment provides a package having a reduced thickness (see col. 3/lls. 17-40). Somaki (e.g. fig. 6) teaches a first and a second interconnect (13 a, b) wherein the first and second interconnects are solder balls. According to Somaki this embodiment allows higher shear strain tolerances, greater reliability and higher conductivity (col. 3/lls. 30-40). It would have been obvious to one of ordinary skill in the art at the time the invention was made to make the second portion of the first interconnect disclosed by Taniguchi recessed beneath the opening and to connect the first and second interconnects within the opening to make a package having a reduced thickness as taught by Lee and to electrically couple a double data rate memory to the integrated circuit die disclosed by Taniguchi in view of Lee in order to increase the operation speed of the system as suggested by Chang and to use solder balls as first and second interconnects as suggested by Somaki to allow for higher shear strain tolerances, greater reliability and higher conductivity.

16. Regarding claim 17, Taniguchi shows that the second circuit package is coupled to the mold compound (i.e. thermally).

17. Regarding claim 18, Taniguchi (e.g. fig. 18) shows a second integrated circuit 4a coupled to the first integrated circuit die, in contact with the mold compound, and electrically coupled to the integrated circuit package.

18. Regarding claim 19, Chang shows a mother board 200 electrically coupled to the integrated circuit die and to the memory.

### ***Response to Arguments***

19. Applicant's arguments filed on 3/27/2007 have been considered but are moot in view of the new ground(s) of rejection.

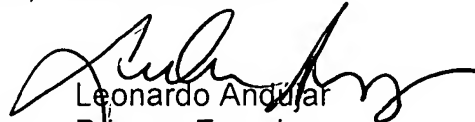
### ***Conclusion***

20. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Leonardo Andújar whose telephone number is 571-272-1912. The examiner can normally be reached on Mon through Thu from 9:00 AM to 7:30 PM EST.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Sue Purvis can be reached on 571-272-1236. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Art Unit: 2826

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

  
Leonardo Andujar  
Primary Examiner  
Art Unit 2826

7/21/2007